Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/662,164	CHENG ET AL.
Examiner	Art Unit
Maikhanh Nguyen	2176

_	SEARCHED			
Class	Subclass	Date	Examiner	
715	530	5/1/2006	MK	
713	161,165	5/1/2006	MK	
713	166,170	5/1/2006	MK	
713	176	5/1/2006	МК	
707	10	5/1/2006	MK	
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Inventor Name Search	5/1/2006	МК
West Search (USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB)	5/1/2006	МК